

<b>Notice of References Cited</b>	Application/Control No. 09/871,287	Applicant(s)/Patent Under Reexamination KOCIMSKI, STANISLAW M.	
	Examiner Bryan Bui	Art Unit 2863	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,808,735	09-1998	Lee et al.	356/237.2
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
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**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Davis baselt, Atomic force microscopy, California Institute of technilgy, copy right 1993, 10 pages.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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